Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination
10/560,672	BAYLY ET AL.
Examiner	Art Unit
Karen Cheng	1626

SEARCHED					
Class	Subclass	Date	Examiner		
514	329	7/20/2007	кс		
514	398	7/20/2007	кс		
546	192	7/20/2007	кс		
546	330	. 7/20/2007	кс		
548	335.1	7/20/2007	кс		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
		,		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
STN Structure Search (see attached)	7/11/2007	кс	
Inventor Name Search (EDan)	7/12/2007	кс	
EAST Search (see attached)	7/20/2007	кс	
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